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GaN Power Devices and Applications

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Message from the Guest Editors

This Special Issue seeks high-quality contributions that address latent challenges in GaN power devices and applications. Survey and research papers detailing theoretical and experimental developments are welcome. The topics of interest include, but are not limited to the following:

- Smart gate drivers for GaN, including silicon and monolithic solution;
- Novel power architecture and circuit design for high power density and fast transient;
- Physics mechanism of device instability and reliability;
- Novel device and circuit design for reliability improvement.











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Message from the Editor-in-Chief

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